

FORM PTO-1449  
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

SERIAL NO.

TI-31076

09/864,509

## LIST OF DOCUMENTS CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT

Lee D. Whetsel

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2133

MAY 27 2005

## U.S. PATENT DOCUMENTS

EXAMINE TRADE MARK	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
CB	3,633,100	1/4/1972	Heilweil, et al.	324	73	5/12/1970
	3,651,315	3/21/1972	Collins	235	151.31	4/29/1970
	3,657,527	4/18/1972	Kassabgi, et al.	235	153	10/16/1969
	3,723,868	3/27/1973	Foster	324	73 AT	1/21/1972
	3,739,193	6/12/1973	Pryor	307	205	1/11/1971
	3,789,359	1/29/1974	Clark, Jr., et al.	340	146.1D	10/4/1972
	3,824,678	7/23/1974	Harris, et al.	29	578	8/31/1970
	3,826,909	7/30/1974	Ivashin	235	153 AC	3/29/1973
	3,831,149	8/20/1974	Job	340	172.5	2/14/1973
	3,838,264	9/24/1974	Maker	235	153 AM	11/23/1971
	3,873,818	3/25/1975	Barnard	253	153 AC	10/29/1973
	3,976,940	8/24/1976	Chau, et al.	324	73 R	2/25/1975
	4,023,142	5/10/1977	Woessner	340	172.5	4/14/1975
	4,066,882	1/3/1978	Esposito	235	302	8/16/1976
	4,086,375	4/25/1978	LaChapelle, Jr., et al.	427	90	11/7/1975
	4,092,733	5/30/1978	Coontz, et al.	365	200	5/7/1976
	4,108,359	8/22/1978	Proto	235	304	3/30/1977
	4,146,835	3/27/1979	Chnapko, et al.	324	73 R	3/8/1978
	4,161,276	7/17/1979	Sacher, t al.	235	302	3/1/1978
	4,216,539	8/5/1980	Raymond, et al.	371	20	5/5/1978
	4,242,751	12/30/1980	Henckels, et al.	371	26	2/24/1976
	4,264,807	4/28/1981	Moen, et al.	235	92 GD	4/9/1979
	4,268,902	5/19/1981	Berglund, et al.	364	200	10/23/1978
	4,286,173	8/25/1981	Oka, et al.	307	440	3/27/1978
	4,308,616	12/29/1981	Timoc	371	23	5/29/1979
	4,309,767	1/5/1982	Andow, et al.	371	24	8/21/1979
	4,312,066	1/19/1982	Bantz, et al.	371	16	12/28/1979
	4,339,710	7/13/1982	Hapke	324	73 R	2/12/1979
	4,357,703	11/2/1982	Van Brunt	371	15	10/9/1980
	4,365,334	12/21/1982	Smith, et al.	371	27	2/9/1981
	4,366,478	12/28/1982	Masuda, et al.	340	825	1/5/1981
	4,390,969	6/1/1983	Hayes	395	550	4/21/1980
	4,426,697	1/1/1984	Petersen, et al.	340	825.52	1/24/1981
CB	4,433,413	2/21/1984	Fasang	371	25	10/22/1981

EXAMINER

Cynthia R. Burt

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FORM PTO-1449  
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

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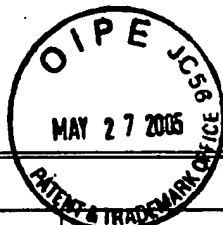
TI-31076

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## U.S. PATENT DOCUMENTS

+EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
CB	4,439,858	3/27/1984	Petersen	371	20	5/28/1981
	4,441,075	4/3/1984	McMahon	324	73 R	7/2/1981
	4,483,002	11/13/1984	Groom, Jr., et al.	371	29	4/19/1982
	4,484,329	11/20/1984	Slamka, et al.	371	25	8/10/1981
	4,488,259	12/11/1984	Mercy	364	900	10/29/1982
	4,493,077	1/8/1985	Agrawal, et al.	371	25	9/9/1982
	4,494,066	1/15/1985	Goel, et al.	324	73 R	7/2/1981
	4,498,172	2/5/1985	Bhavsar	371	25	7/26/1982
	4,503,536	3/5/1985	Panzer	371	25	9/16/1982
	4,504,784	3/12/1985	Goel, et al.	324	73R	7/2/1981
	4,513,373	4/1/1985	Sheets	364	200	12/28/1982
	4,513,418	4/23/1985	Bardell, Jr, et al.	371	25	11/8/1982
	4,514,845	4/30/1985	Starr	371	15	8/23/1982
	4,519,078	5/21/1985	Komonytshy	371	25	9/29/1982
	4,534,028	8/6/1985	Trischler	371	25	12/1/1983
	4,553,090	11/12/1985	Hatano, et al.	324	73 AT	7/23/1980
	4,575,674	3/11/1986	Bass, et al.	324	73 R	7/1/1983
	4,577,318	3/18/1986	Whitacre, et al.	371	1	11/14/1983
	4,587,609	5/1/1986	Boudreau, et al.	395	726	7/1/1983
	4,594,711	6/10/1986	Thatte	371	25	11/10/1983
	4,597,042	6/24/1986	d'Angeac	364	200	9/13/1983
	4,597,080	6/24/1986	Thatte, et al.	371	25	11/14/1983
	4,598,401	7/1/1986	Whelan	371	25	6/25/1984
	4,601,034	7/15/1986	Sridhar	371	25	3/30/1984
	4,602,210	7/22/1986	Fasang, et al.	324	73	12/28/1984
	4,612,499	9/16/1986	Andresen, et al.	324	73 R	11/7/1983
	4,615,029	9/30/1986	Hu, et al.	370	89	12/3/1984
	4,618,956	10/21/1986	Horst	371	68	9/29/1983
	4,620,302	10/28/1986	Binoeder, et al.	371	1	1/6/1984
	4,621,363	11/4/1986	Blum	371	25	12/6/1984
	4,627,018	12/1/1986	Trost, et al.	395	476	9/8/1983
	4,628,511	12/9/1986	Stitzlein, et al.	371	22	2/25/1982
OB	4,635,193	1/6/1987	Moyer, et al.	364	200	6/27/1984
	4,635,261	1/6/1987	Anderson, et al.	371	25	1/26/1985

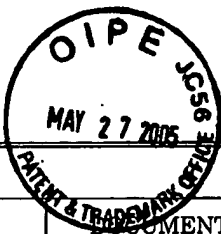
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FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. TI-31076		SERIAL NO. 09/864,509	
LIST OF DOCUMENTS CITED BY APPLICANT <small>(Use several sheets if necessary)</small>				APPLICANT Lee D. Whetsel			
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U.S. PATENT DOCUMENTS							
+EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)	
cb	4,638,313	1/20/1987	Sherwood, et al.	340	825.52	11/8/1984	
	4,642,561	2/10/1987	Groves, et al.	324	73 R	6/13/1983	
	4,646,298	2/1/1987	Laws, et al.	371	16	5/1/1984	
	4,646,299	2/24/1987	Schinabeck, et al.	371	20	8/1/1983	
	4,651,088	3/17/1987	Sawada	324	73R	5/6/1985	
	4,669,061	5/26/1987	Bhavsar	365	154	12/21/1984	
	4,672,307	6/9/1987	Breuer, et al.	324	73 R	12/20/1985	
	4,674,089	6/16/1987	Poret, et al.	371	25	4/16/1985	
	4,679,192	7/1/1987	Vanbrabant	340	825.52	1/24/1986	
	4,680,539	7/14/1987	Tsai	324	73	12/30/1983	
	4,680,733	7/14/1987	Duforestel	364	900	10/29/1984	
	4,683,569	7/28/1987	Rubin	371	25	10/21/1985	
	4,687,988	8/18/1987	Eichelberger, et al.	324	73 AT	6/24/1985	
	4,694,293	9/15/1987	Sugiyama, et al.	340	825.68	9/16/1985	
	4,698,588	10/6/1987	Hwang, et al.	324	73 R	10/23/1985	
	4,701,916	10/20/1987	Naven, et al.	371	15	3/17/1986	
	4,701,920	10/20/1987	Resnick, et al.	371	25	11/8/1985	
	4,701,921	10/20/1987	Powell, et al.	371	25	10/23/1985	
	4,710,931	12/1/1987	Bellay, et al.	371	25	10/23/1985	
	4,710,932	12/1/1987	Hiroshi	371	25	1/15/1986	
	4,710,933	12/1/1987	Powell, et al.	371	25	10/23/1985	
	4,734,921	3/29/1988	Giangano, et al.	377	72	11/25/1986	
	4,740,970	4/26/1988	Burrows, et al.	371	15	12/11/1985	
	4,743,841	5/10/1988	Takeuchi	324	73 R	5/20/1985	
	4,745,355	5/17/1988	Eichelberger, et al.	324	73 R	6/24/1985	
	4,752,929	6/21/1988	Kantz, et al.	371	21	3/25/1986	
	4,759,019	7/19/1988	Bentley, et al.	371	3	7/10/1986	
	4,763,066	8/9/1988	Yeung, et al.	324	73R	7/23/1986	
	4,764,926	8/16/1988	Knight, et al.	371	25	12/11/1985	
	4,777,616	10/11/1988	Moore, et al.	364	900	5/12/1986	
4,783,785	11/8/1988	Hanta	371	25	1/5/1987		
4,788,683	11/29/1988	Hester, et al.	371	20	1/14/1986		
4,791,358	12/13/1988	Sauerwald, et al.	324	73 R	9/2/1986		
cb	4,799,004	1/17/1989	Mori	324	73 R	1/25/1988	

EXAMINER <i>Cynthia Burt</i>	DATE CONSIDERED 8-11-05
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U.S. PATENT DOCUMENTS							
+EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)	
CS	4,799,052	1/1/1989	Near, et al.	340	825.52	1/13/1986	
	4,800,418	1/24/1989	Natsui	357	68	9/6/1984	
	4,801,870	1/31/1989	Eichelberger, et al.	324	73R	6/24/1985	
	4,802,163	1/31/1989	Hirabayshi	371	15	12/29/1986	
	4,808,844	2/28/1989	Ozaki, et al.	307	243	4/17/1986	
	4,811,299	3/7/1989	Miyazawa, et al.	365	201	4/22/1987	
	4,812,678	3/14/1989	Abe	307	443	3/23/1987	
	4,817,093	3/28/1989	Jacobs, et al.	371	25	6/18/1987	
	4,819,234	4/4/1989	Huber	371	19	5/1/1987	
	4,821,269	4/11/1989	Jackson, et al.	371	16	10/23/1986	
	4,825,439	4/25/1989	Sakashita, et al.	371	15	8/18/1987	
	4,833,395	5/23/1989	Sasaki, et al.	324	73 R	10/23/1987	
	4,833,676	5/23/1989	Koo	371	15	7/30/1987	
	4,855,954	8/8/1989	Turner, et al.	365	185	3/4/1985	
	4,857,835	8/15/1989	Whetsel	324	73	11/5/1987	
	4,860,288	8/22/1989	Teske, et al.	371	1	10/23/1987	
	4,860,290	8/22/1989	Daniels, et al.	371	25	6/2/1987	
	4,862,071	8/29/1989	Sato, et al.	324	73 R	11/18/1988	
	4,862,072	8/29/1989	Harris, et al.	324	73 R	9/8/1988	
	4,864,570	9/5/1989	Savaglio, et al.	371	22.4	6/29/1987	
	4,864,579	9/5/1989	Kishida, et al.	371	22.3	8/3/1987	
	4,866,508	9/12/1989	Eichelberger, et al.	357	74	9/26/1986	
	4,870,345	9/26/1989	Tomioka, et al.	371	22.3	8/3/1987	
	4,872,169	10/3/1989	Whetsel	371	22.3	3/6/1987	
	4,875,003	10/17/1989	Burke	324	73 R	2/21/1989	
	4,878,168	10/31/1989	Johnson, et al.	364	200	10/29/1986	
	4,879,717	11/7/1989	Sauerwald, et al.	371	22.3	9/2/1986	
	4,887,262	12/12/1989	van Veldhuizen	370	85.1	3/15/1988	
	4,887,267	12/12/1989	Kanuma	371	22.3	12/28/1987	
	4,893,072	1/9/1990	Matsumoto	371	223	6/22/1988	
4,894,830	1/16/1990	Kawai	371	22.3	1/19/1988		
4,896,262	1/23/1990	Wayama, et al.	364	200	2/22/1985		
CB	4,897,842	1/30/1990	Herz, et al.	371	22.4	11/5/1987	


EXAMINER <i>Cynthia Britt</i>	DATE CONSIDERED <i>8-11-05</i>
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U.S. PATENT DOCUMENTS						
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<i>DB</i> <div style="border-left: 1px solid black; height: 200px; margin: 0 auto; width: 20px;"></div>	4,899,273	2/6/1990	Omoda, et al.	364	200	12/10/1986
	4,903,266	2/20/1990	Hack	371	21.2	4/29/1988
	4,907,230	3/6/1990	Heller, et al.	371	22.1	2/29/1988
	4,910,735	3/20/1990	Yamashita	371	22.4	12/17/1987
	4,912,633	3/27/1990	Schweizer, et al	364	200	10/24/1988
	4,912,709	3/27/1990	Teske, et al.	371	22.1	10/23/1987
	4,918,379	4/17/1990	Jongepier	324	73.1	8/31/1988
	4,924,468	5/8/1990	Horak, et al.	371	22.1	11/16/1988
	4,926,425	5/15/1990	Hedtke, et al.	371	22.6	6/9/1988
	4,929,889	5/29/1990	Seiler, et al.	371	22.3	6/13/1988
	4,930,216	6/5/1990	Nelson	29	854	3/10/1989
	4,931,722	6/5/1990	Stoica	371	22.5	11/7/1985
	4,931,723	6/5/1990	Jeffrey, et al.	371	22.3	12/18/1985
	4,935,868	6/1/1990	DuLac	364	200	11/28/1988
	4,937,826	6/26/1990	Gheewala, et al.	371	22.1	9/9/1988
	4,943,966	7/24/1990	Giunta, et al.	371	11.1	4/8/1988
	4,945,536	7/31/1990	Hancu	371	22.3	9/9/1988
	4,947,106	8/7/1990	Chism	324	73.1	3/31/1988
	4,947,357	8/7/1990	Stewart, et al.	371	22.3	2/24/1988
	4,956,602	9/11/1990	Parrish	324	158 R	2/14/1989
	4,961,053	10/2/1990	Krug	324	158 R	7/24/1985
	4,969,121	11/6/1990	Chan, et al.	364	900	3/2/1987
	4,974,192	11/27/1990	Face, et al	364	900	7/23/1987
	4,974,226	11/27/1990	Fujimori, et al.	371	22.3	9/22/1988
	4,989,209	1/29/1991	Littlebury, et al.	371	22.1	3/24/1989
	4,992,985	2/12/1991	Miyazawa, et al.	365	201	4/22/1987
	5,001,713	3/19/1991	Whetsel	371	22.3	2/8/1989
	5,008,618	4/16/1991	Van Der Star	324	158 R	1/23/1990
5,008,885	4/16/1991	Huang, et al.	371	3	12/29/1988	
5,012,185	4/30/1991	Ohfuji	324	158 R	10/16/1989	
5,014,186	5/1/1991	Chisholm	395	850	8/1/1986	
5,023,872	6/11/1991	Annamalai	371	5.1	3/25/1988	
EXAMINER <i>Cynthia Brutt</i>			DATE CONSIDERED <i>8-11-05</i>			
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					U.S. PATENT DOCUMENTS			
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<div style="font-size: 2em; font-family: cursive;">CB</div>	5,042,005	8/20/1991	Miller, et al.	364	900	8/19/1988		
	5,048,021	9/10/1991	Jarwala, et al.	371	22.3	8/28/1989		
	5,051,996	9/24/1991	Bergeson, et al.	371	22.4	3/27/1989		
	5,053,949	10/1/1991	Allison, et al.	364	200	4/3/1989		
	5,054,024	10/1/1991	Whetsel	371	22.3	8/9/1989		
	5,056,093	10/8/1991	Whetsel	371	22.3	8/9/1989		
	5,056,094	10/8/1991	Whetsel	371	25.1	6/9/1989		
	5,070,296	12/3/1991	Priebe	324	73.1	6/22/1990		
	5,070,297	12/3/1991	Kwon, et al.	324	158 P	6/4/1990		
	5,077,740	12/31/1991	Kanuma	371	22.3	1/30/1989		
	5,084,814	1/28/1992	Vaglica, et al.	395	325	10/30/1987		
	5,084,874	1/28/1992	Whetsel	371	22.3	9/7/1988		
	5,090,015	2/18/1992	Dabbish, et al.	371	22.5	2/6/1989		
	5,090,035	2/18/1992	Murase	377	72	1/22/1991		
	5,103,450	4/7/1992	Whetsel	714	724	2/8/1989		
	5,107,148	4/21/1992	Millman	307	473	4/12/1991		
	5,107,489	4/1/1992	Brown, et al.	370	58.2	10/30/1989		
	5,109,190	4/28/1992	Sahashita, et al.	324	158 R	2/22/1991		
	5,109,383	4/28/1992	Chujo	371	22.3	9/1/1989		
	5,115,191	5/19/1992	Yoshimori	324	158 R	6/11/1991		
	5,115,435	5/1/1992	Langford, II, et al.	371	22.1	10/19/1989		
	5,126,286	6/30/1992	Chance	437	203	10/5/1990		
	5,128,664	7/1/1992	Bishop	340	825.52	5/5/1986		
	5,130,988	7/1/1992	Wilcox, et al.	371	22.3	9/17/1990		
	5,132,635	7/1/1992	Kennedy	371	22.3	3/5/1991		
	5,133,062	7/1/1992	Joshi, et al.	395	500	3/6/1986		
	5,134,314	7/28/1992	Wehrmacher	307	443	12/18/1990		
	5,150,044	9/1/1992	Hashizume, et al.	324	158 R	3/22/1991		
	5,150,047	9/22/1992	Saito, et al.	324	158 R	7/17/1990		
	5,155,432	10/13/1992	Mahoney	324	158 R	10/7/1987		
5,159,465	10/1/1992	Maemura, et al.	326	73	10/5/1988			
5,161,160	11/3/1992	Yaguchi, et al.	371	22.3	2/1/1990			
5,165,022	11/1/1992	Erhard, et al.	395	275	11/23/1989			
EXAMINER <div style="font-size: 1.5em; font-family: cursive;">Cynthia Barth</div>				DATE CONSIDERED <div style="font-size: 1.5em; font-family: cursive;">8-11-05</div>				
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LIST OF DOCUMENTS CITED BY APPLICANT <small>(Use several sheets if necessary)</small>				APPLICANT Lee D. Whetsel	
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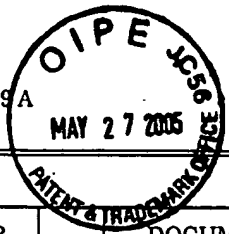


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	5,170,398	12/8/1992	Fujieda, et al.	371	27	7/18/1990	
	5,172,377	12/1/1992	Robinson, et al.	371	22.3	9/7/1990	
	5,173,906	12/22/1992	Dreibelbis, et al.	371	22.5	8/31/1990	
	5,175,447	12/29/1992	Kawasaki, et al.	307	480	4/19/1991	
	5,187,795	2/1/1993	Balmforth, et al.	395	800	1/27/1989	
	5,191,653	3/1/1993	Banks, et al.	395	275	12/28/1990	
	5,202,625	4/13/1993	Farwell	324	158 R	7/3/1991	
	5,206,545	4/27/1993	Huang	307	443	2/5/1991	
	5,210,759	5/11/1993	DeWitt, et al.	371	22.3	11/19/1990	
	5,214,760	5/1/1993	Hammond, et al.	395	250	8/26/1988	
	5,214,774	5/1/1993	Welsch, et al.	455	11.1	7/30/1990	
	5,218,702	6/1/1993	Kirtland	395	298	7/6/1988	
	5,222,068	6/22/1993	Burchard	371	22.3	3/13/1992	
	5,241,265	8/31/1993	McDonnell, et al.	324	158 R	3/26/1992	
	5,241,266	8/31/1993	Ahmad, et al.	324	158 R	4/10/1992	
	5,252,917	10/12/1993	Kadowaki	324	158 R	4/24/1991	
	5,254,942	10/19/1993	D'Souza, et al.	324	158 R	4/25/1991	
	5,258,985	11/2/1993	Spence, et al.	371	22.4	11/12/1991	
	5,260,949	11/9/1993	Hashizume, et al.	371	22.3	12/14/1990	
	5,276,807	1/1/1994	Kodoma, et al.	395	309	4/13/1987	
	5,278,494	1/11/1994	Obigane	324	158 F	2/19/1992	
	5,279,975	1/18/1994	Devereaux, et al.	437	8	2/7/1992	
	5,286,656	2/15/1994	Keown, et al.	437	7	11/2/1992	
	5,291,025	3/1/1994	Smith	250	561	11/30/1992	
	5,297,277	3/22/1994	Dein, et al.	395	575	8/31/1990	
	5,303,148	4/12/1994	Mattson, et al.	364	413.01	11/27/1987	
	5,313,158	5/17/1994	Joosten, et al.	324	158 R	1/12/1993	
	5,315,241	5/24/1994	Ewers	324	158 R	9/18/1991	
	5,317,205	5/31/1994	Sato	307	443	6/2/1992	
	5,319,754	6/1/1994	Meinecke, et al.	395	325	10/3/1991	
	CB	5,321,322	6/14/1994	Verheyen, et al.	307	465.1	3/24/1993

EXAMINER <i>Cynthia Butt</i>	DATE CONSIDERED <i>8-11-05</i>
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	5,334,857	8/2/1994	Mennitt, et al.	257	48	4/6/1992	
	5,343,478	8/1/1994	James, et al.	371	22.3	11/27/1991	
	5,353,308	10/4/1994	Whetsel	371	22.3	8/6/1990	
	5,355,369	10/11/1994	Greenberger, et al.	371	22.3	4/26/1991	
	5,366,906	11/22/1994	Wojnarowski, et al.	437	8	10/16/1992	
	5,371,390	12/6/1994	Mohsen	257	209	11/4/1992	
	5,377,198	12/27/1994	Simpson, et al.	371	22.3	11/27/1991	
	5,388,216	2/1/1995	Oh	395	849	10/3/1991	
	5,389,556	2/14/1995	Rostoker, et al.	437	8	7/2/1992	
	5,389,873	2/14/1995	Ishii, et al.	324	158.1	5/18/1993	
	5,390,131	2/14/1995	Rohrbaugh, et al.	364	490	4/6/1992	
	5,391,984	2/14/1995	Worley	324	158.1	11/1/1991	
	5,396,170	3/7/1995	D'Souza, et al.	324	158.1	4/25/1991	
	5,399,505	3/21/1995	Dasse, et al.	437	8	7/23/1993	
	5,420,874	5/30/1995	Kromer	371	47.1	4/20/1993	
	5,424,651	6/13/1995	Green, et al.	324	754	3/27/1992	
	5,426,650	6/20/1995	Ganapathy, et al.	371	22.3	11/24/1992	
	5,428,622	6/27/1995	Kuban et al.	371	22.3	3/5/1993	
	5,430,735	7/4/1995	Sauerwald, et al.	371	22.3	10/10/1989	
	5,434,804	7/18/1995	Bock, et al.	364	579	12/29/1993	
	5,442,282	8/15/1995	Rostoker, et al.	324	158.1	7/2/1992	
	5,446,395	8/29/1995	Goto	324	763	9/21/1993	
	5,448,166	9/5/1995	Parker et al.	324	158	1/3/1992	
	5,448,525	9/5/1995	Sturges	365	201	3/10/1994	
	5,448,576	9/5/1995	Russell	371	22.3	10/29/1992	
	5,450,415	9/12/1995	Kamada	371	22.3	11/19/1993	
	5,453,992	9/26/1995	Whetsel	371	22.3	8/2/1993	
	5,457,400	10/10/1995	Ahmad, et al.	324	763	4/10/1992	
5,469,473	11/21/1995	McClear, et al.	375	219	4/15/1994		
5,471,481	11/28/1995	Okumoto, et al.	371	22.3	5/17/1993		
CB	5,481,734	1/1/1996	Yoshida	395	775	12/13/1990	

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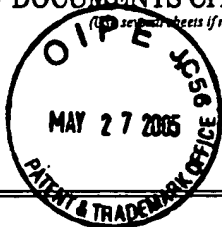


U.S. PATENT DOCUMENTS							
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	5,488,614	1/30/1996	Shima	371	22.3	3/23/1993	
	5,488,728	1/30/1996	Dreyer	395	726	4/27/1992	
	5,489,538	2/6/1996	Rostoker, et al.	437	8	8/21/1992	
	5,490,151	2/6/1996	Feger, et al.	371	22.3	7/26/1993	
	5,491,666	2/13/1996	Sturges	365	201	3/10/1994	
	5,491,699	2/13/1996	Scheuermann, et al.	371	22.1	2/2/1994	
	5,495,487	2/27/1996	Whetsel	714	736	9/7/1988	
	5,497,378	3/5/1996	Amini et al.	714	727	11/2/1993	
	5,526,310	6/11/1996	Dondale	365	196	2/14/1995	
	5,526,365	6/11/1996	Whetsel	371	22.3	6/30/1993	
	5,532,174	7/2/1996	Corrigan	437	8	4/22/1994	
	5,534,786	7/9/1996	Kaneko, et al.	324	760	2/22/1995	
	5,535,222	7/9/1996	Le	371	22	12/23/1993	
	5,535,331	7/9/1996	Swoboda, et al.	714	28	5/4/1989	
	5,541,935	7/30/1996	Waterson	371	22.5	5/26/1995	
	5,544,174	8/6/1996	Abend	371	22.3	3/17/1994	
	5,548,781	8/11/1996	Huang	395	831	7/8/1993	
	5,550,843	8/27/1996	Yee	371	22.3	4/1/1994	
	5,557,573	9/17/1996	McClure	365	201	8/21/1995	
	5,568,492	10/22/1996	Flint, et al.	371	22.1	6/6/1994	
	5,568,493	10/22/1996	Morris	324	73	10/16/1992	
	5,574,730	11/12/1996	End, III et al.	714	724	1/31/1995	
	5,576,980	11/19/1996	Whetsel	364	579	6/28/1991	
	5,577,052	11/19/1996	Morris	714	726	10/16/1992	
	5,581,541	12/3/1996	Whetsel	370	241	6/17/1992	
	5,590,275	12/31/1996	Van Berkel, et al.	395	183.06	2/14/1995	
	5,592,493	1/7/1997	Crouch et al.	371	22.3	9/13/1994	
	5,600,788	2/4/1997	Lofgren et al.	395	183	1/19/1994	
	5,608,335	3/4/1997	Taillet	324	763	12/27/1993	
5,608,736	3/4/1997	Bradford, et al.	371	22.3	6/6/1991		
CB	5,610,530	3/11/1997	Whetsel	324	763	10/26/1994	

EXAMINER <i>Cynthia Booth</i>	DATE CONSIDERED <i>8-11-05</i>
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## U.S. PATENT DOCUMENTS

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	5,627,840	5/6/1997	Hundertmark, et al.	371	22.3	9/15/1995
	5,627,842	5/6/1997	Brown et al.	714	727	1/21/1993
	5,640,404	6/17/1997	Satish	371	22.3	8/5/1996
	5,648,661	7/15/1997	Rostoker, et al.	257	48	7/2/1992
	5,659,257	8/19/1997	Lu, et al.	324	763	7/5/1994
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	5,673,276	9/30/1997	Jarwala et al.	714	727	12/27/1993
	5,677,915	10/14/1997	Whetsel	371	22.3	8/18/1993
	5,685,004	11/4/1997	Bruce, et al.	395	800	3/6/1990
	5,687,179	11/11/1997	Whetsel, et al.	371	22.3	3/30/1990
	5,701,307	12/23/1997	Whetsel	371	22.3	12/16/1994
	5,706,235	1/6/1998	Roohparvar, et al.	365	201	7/28/1995
	5,706,297	1/6/1998	Jeppesen, III, et al.	371	22.3	8/24/1995
	5,708,773	1/13/1998	Jeppesen, III et al.	714	30	7/20/1995
	5,710,779	1/20/1998	Whetsel	371	22.3	4/9/1996
	5,715,171	2/3/1998	Mori, et al.	364	490	9/26/1995
	5,715,254	2/3/1998	Whetsel	371	22.3	11/21/1994
	5,715,255	2/3/1998	Whetsel	371	22.3	11/21/1994
	5,719,876	2/17/1998	Warren	371	22.3	8/24/1995
	5,719,878	2/17/1998	Yu, et al.	371	22.3	12/4/1995
	5,744,949	4/28/1998	Whetsel	324	158.1	8/17/1993
	5,760,643	7/2/1998	Whetsel			10/31/1995
	5,781,560	7/14/1998	Kawano et al.	714	727	2/28/1995
	5,802,270	9/1/1998	Ko, et al.	395	183.03	9/21/1989
	5,805,609	9/8/1998	Mote, Jr.	714	726	6/7/1995
	5,805,792	9/8/1998	Swoboda, et al.	395	183.04	7/31/1989
	5,825,785	10/20/1998	Barry, et al.	371	22.4	3/24/1996
<i>CB</i>	5,828,824	10/27/1998	Swoboda	395	183.01	12/16/1996

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DATE CONSIDERED

*Cynthia Butth*

*8-11-05*

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	5,841,670	11/24/1998	Swoboda	364	578	3/9/1994	
	5,841,791	11/24/1998	Hashizume	371	22.3	3/13/1992	
	5,847,561	12/8/1998	Whetsel	324	158.1	7/31/1995	
	5,862,152	1/19/1999	Handly, et al.	371	22.32	11/13/1995	
	5,872,908	2/16/1999	Whetsel	395	183.06	5/31/1995	
	5,883,524	3/16/1999	Whetsel	326	16	5/31/1995	
	5,884,023	3/16/1999	Swoboda, et al.	395	183.06	12/14/1995	
	5,887,001	3/23/1999	Russell	714	726	12/13/1995	
	5,887,004	3/23/1999	Walther	371	22.31	3/28/1997	
	5,905,738	3/18/1999	Whetsel	371	22.4	6/30/1989	
	5,907,562	5/25/1999	Wrape et al.	371	22.31	7/31/1996	
	5,949,984	9/7/1999	Fujitaka	395	500	12/1/1997	
	5,958,072	9/28/1999	Jacobs, et al.	714	30	1/13/1997	
	5,968,191	10/19/1999	Thatcher, et al.	714	723	6/2/1993	
	5,968,192	10/19/1999	Kornachuk et al.	714	724	5/9/1997	
	6,000,051	12/7/1999	Nadeau-Dostie et al.	714	727	10/10/1997	
	6,006,343	12/21/1999	Whetsel	714	28	7/30/1993	
	6,028,983	2/22/2000	Jaber	395	183.06	9/19/1996	
	6,035,431	3/7/2000	Higashida	714	726	2/26/1998	
	6,037,794	3/14/2000	Yamamoto, et al.	324	760	8/5/1998	
	6,046,600	4/4/2000	Whetsel	324	763	10/31/1995	
	6,055,656	4/25/2000	Wilson, Jr., et al.,	714	724	5/2/1995	
	6,073,254	6/6/2000	Whetsel	714	30	8/30/1996	
	6,115,763	9/5/2000	Douskey, et al.	710	72	3/5/1998	
	6,158,035	12/5/2000	Whetsel, et al.	714	731	3/30/1990	
	6,199,182	3/6/2001	Whetsel	714	724	3/27/1997	
	6,223,315	4/24/2001	Whetsel	714	727	6/30/1997	
	6,242,269	6/5/2001	Whetsel	438	11	11/3/1997	
	6,260,165	7/10/2001	Whetsel	714	727	10/18/1996	
6,286,121	9/4/2001	Osawa, et al.	714	738	10/22/1998		
6,324,614	11/27/2001	Whetsel	710	130	8/30/1996		
6,324,662	11/27/2001	Haroun, et al.	714	724	3/27/1998		



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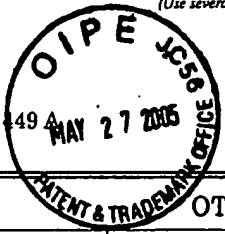
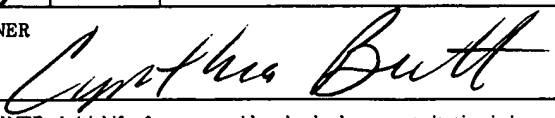
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	EP 0,148,403	7/17/1985	Europe	G01	R31/28	X	
	EP 0,190,494	8/13/1986	Europe	G01	R31/28	X	
	EP 0,195,164	9/24/1986	Europe	G01	R31/28	X	
	EP 0,273,821	7/6/1988	Europe	G01	R31/28	X	
	EP 0,310,152	4/5/1989	Europe	G01	R31/28	X	
	EP 0,315,475 A2	10/5/1989	Europe	G01	R31/28	X	
	EP 0,518,550 A2	12/16/1992	Europe	G06F	37586		
	EP 0,522,413 A2	1/13/1993	Europe	G06F	37586		
	EP 0,604,032 A2	6/29/1994	Europe	G06F	37586		
	GB 2,220,272 A	1/4/1990	UK	G01R	31/28		
	GB 2,266,965 A	11/17/1993	UK	G01R	31/28		
	JP 01-038674 A	2/8/1989	Japan	G01R	31/28	X	
	JP 01-043773	2/16/1989	Japan	G01	R31/28	X	
	JP 01-068167 A	3/14/1989	Japan	H04M	3/22	X	
	JP 01-079673(A)	3/24/1989	Japan	G01R31	28	X	
	JP 01-110274	4/26/1989	Japan	G01R31	28	X	
	JP 01-170873	7/5/1989	Japan	G01R31	28	X	
	JP 02-016642 (A)	1/19/1990	Japan	G06F11	22	X	
	JP 02-052165	4/13/1990	Japan	G01R	13/28	X	
	JP 02-062984	3/2/1990	Japan	G01R	31/28	X	
	JP 05-142,298	6/8/1993	Japan	G01	R31/28	X	
	JP 57-094857 A	6/12/1982	Japan	G06F	37582	X	
	JP 57-209546	12/22/1982	Japan	G06F11	20	X	
	JP 58-155599	9/16/1983	Japan	G11	C29	X	
	JP 58-191021 A	11/8/1983	Japan	G06F	36586	X	
	JP 59-210382	11/29/1984	Japan	G01R	31/28	X	
	JP 60-140834 A	7/25/1985	Japan	H01L	21/66	X	
	JP 60-252958	12/13/1985	Japan	G06F	11/22	X	
	JP 60-262073	12/25/1985	Japan	G01R	31/28	X	
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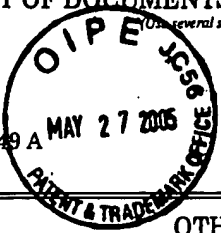


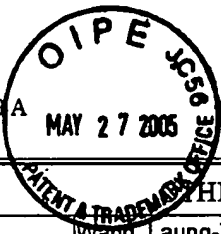
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				FILING DATE 5/23/2001	GROUP 2133
Form PTO 1449A 					
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>					
CB		"IEEE Standard Test Access Port and Boundary-Scan Architecture," IEEE Computer Society, Oct. 21, 1993.			10/21/1993
CB		"SCANPSC110F SCAN.TM. Bridge Hierarchical and Multidrop Addressable JTAG Port (IEEE 1149.1 System Test Support)," National Semiconductor, Sep. 1993, pp. 1-32.			9/1/1993
CB		"SN54ACT8999, SN74ACT8999 Scan Path Selectors with 8-Bit Bidirectional Data Buses," Texas Instruments Product Review, Jun. 1990, pp. 11-166 to 11-194.			6/1/1990
CB		Adshead, Dave, "Embedded Systems: JTAG Accelerates Debugging Process," Electronic Engineering Times, June 22, 1998, pp 106.			6/22/1998
CB		Avra, LaNae, "A VHSIC ETM-BUS Compatible Test and Maintenance Interface", 1987 International Test Conference, Sept. 1-3, 1987, Paper 41.2, pp. 964-971			9/1/1987
CB		Bhavsar, D., "An Architecture for Extending the IEEE Standard 1149.1 Test Access Port to System Backplanes", International Test Conference 1991, pp. 768-776			1/1/1991
CB		Bhavsar, D., "Chapter 17. Designs that Help Test Interconnect Shorts", IEEE, 1990, pp.183-189			1/1/1990
CB		Bhavsar, D., et al., "Self-Testing by Polynomial Division", Digest of Papers, International Test Conference, 1981, pp.208-216			1/1/1981
CB		Blair, Jack D.; et al., "A 16-Mbit/s Adapter Chip for the IBM Token-Ring Local Area Network", IEEE Journal of Solid-State Circuits, Vol. 24, No. 6, December 1989, pp. 1647-1654			12/1/1989
CB		Breuer, Melvin A.; Lien, Jung-Cheun, "A Test and Maintenance Controller for a Module Containing Testable Chips", 1988 International Test Conference, Sept. 12-14, 1988, Paper 27.1, pp. 502-513			9/12/1988
CB		Bruce, W. C., et al., "Implementing 1149.1 on CMOS Processors", IEEE International Test Conference 1992, Paper BP-91, pp. 999-1006			1/1/1992
CB		Carbine, Adrian and Feltham, Derek, "Pentium Pro Processor Design for Test and Debug," International Test Conference 1997, November 1-6, 1997, pp. 294-303, IEEE Computer Society			11/1/1997
CB		Colwell, Robert P. and Steck, Randy L., "TP 10.4: A 0.6um BiCMOS Processor with Dynamic Execution," 1995 IEEE International Solid-State Circuits Conference, February 15-17, 1995, pp. 176-177			2/15/1995
CB		Dervisoglu, Bulent I., "Using Scan Technology for Debug and Diagnostics in a Workstation Environment", 1988 International Test Conference, Sept. 12-14, 1988, Paper 45.2, pp.976-986			9/12/1988
CB		Dervisoglu, Bulent, "IEEE P1149.2 Description and Status Report", IEEE Design and Test of Computers, September, 1992, pp. 79-81			9/1/1992
CB		Dervisoglu, Bulent, et al., "Shared I/O-Cell Structures: A Framework for Extending the IEEE 1149.1 Boundary-Scan Standard", Int'l Test Conference, October 19, 1998, pp. 908-989			10/19/1998
CB		El-ziq, et al., "A Mixed-Mode Built-In Self-Test Technique Using Scan Path and Signature Analysis", International Test Conference, Oct. 18-20, 1983, pp. 269-274			10/18/1983
EXAMINER 				DATE CONSIDERED 8-11-05	
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Form PTO 1449A MAY 27 2005 PATENT & TRADEMARK OFFICE					
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)					
CB		ETM-Bus Specification, VHSIC Phase 2 Interoperability Standards, December 31, 1985, Version 1.0			12/31/1985
CB		George, David, "Use a reprogrammable approach to boundary scan for FPGAs", EDN, Electrical Design News, Vol. 38, No. 16, August 5, 1993, pp.97-104			8/5/1993
CB		Gerstendorfer, S. et al. "Minimized Power Consumption for Scan-Based BIST", Proceedings International Test Conference, Sept. 28-30, 1999 (IEEE Cat. No. 99CH37034) pp.77-84			9/28/1999
CB		Gott, Robert A., "Embedded Systems: Debugging Embedded Software," pp. 71-73, 76, 78, Computer Design, February 1998			2/1/1998
CB		Haedtke, et al., "Multilevel Self-test for the Factory and Field", Proceedings, Annual Reliability and Maintainability Symposium, 1987			1/1/1987
CB		Hahn, et al., "VLSI Testing By On-Chip Error Detection", IBM Technical Disclosure Bulletin, Vol. 25, No. 2, July 1982			7/1/1982
CB		Heatherington, G. et al., "Logic BIST for Large Industrial Designs: Real Issues and Case Studies," Proceedings International Test Conference, Sept. 28, 1999, IEEE vol. CONF. 30, pp. 358-367			9/28/1999
CB		Hudson, et al., "Integrating BIST And Boundary-Scan On A Board", Proceedings of the National Communications Forum, Sept. 30, 1988, pp. 1796-1800			9/30/1988
CB		Hudson, et al., "Parallel Self-test With Pseudo-Random Test Patterns", International Test Conference, Sept. 1-3, 1987, pp.954-963			9/1/1987
CB		Hunter, C., et al., "Design and Implementation of the 'G2' PowerPC™ 603e™ Embedded Microprocessor Core", IEEE International Test Conference Proceedings, October 18-23, 1998,			10/18/1998
CB		IBM Technical Disclosure Bulletin, "Bidirectional Double Latch", Vol. 28, No. 1, June, 1985			6/1/1985
CB		IBM Technical Disclosure Bulletin, "Self-Contained IBM Performance Monitor for a Personal Computer", December, 1988, Vol. 3, No. 7, pp.376-377			12/1/1988
CB		IBM Technical Disclosure Bulletin, "Test Bus Architecture", Vol. 32, No. 3A, August 1989, pp.21-27			8/1/1989
CB		IEEE P1149.2 - D2.5, "Extended Digital Serial Subset", Unapproved Draft Published for Comment Only, 8/30/1994, pp.1/37			8/30/1994
CB		Intel, "80386 Programmer's Reference Manual 1986", Chapter 12: Debugging, pp. 12-1 - 12-9, 1/18/1988			1/18/1988
CB		Intel, "Intel386™ DX Microprocessor Data Sheet," Section 2.11: Testability, 1988			1/1/1988
CB		Intel, "Microprocessor and Peripheral Handbook", 80386 Preliminary, Section 2.11: Testability, 1988			1/1/1988
CB		Jarwala, Madhuri, "A Framework for Design for Testability of Mixed Analog/Digital Circuits", IEEE 1991 Custom Integrated Circuits Conference, pp. 13.5.1-4			1/1/1991
EXAMINER <i>Cynthia Bratt</i>				DATE CONSIDERED <i>8-11-05</i>	
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Form PTO 1449 A 					
<b>OTHER DOCUMENTS</b> <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>					
CB		Joint Test Action Group, Technical Sub-Committee, "A Standard Boundary Scan Architecture", January 1988			1/1/1988
CB		Jungert, H., et al., "JTAG: Standard Testing of Complex Systems. Part 3: Bus Drivers and Latches with JTAG Test Ports", Elektronik, Messen und Testen, No. 14, July 7, 1989, pp.96-103, with translation			7/7/1989
CB		Kuban, John R. and Bruce, William C, "Self-Testing the Motorola MC6804P2," IEEE Design & Test, May, 1984, earlier version in International Test Conference Proceedings, October 1983			10/1/1983
CB		Laurent, "An Example of Test Strategy for Computer Implemented with VLSI Circuits", IEEE International Conference on computer Design: VLSI in Computers, Oct. 7-10, 1985, pp. 679-682			10/7/1985
CB		Lee, Nai-Chi, "A Hierarchical Analog Test Bus Framework for Testing Mixed-Signal Integrated Circuits and Printed circuit Boards", Journal of Electronic Testing: Theory and Applications, 4(1993), November, No. 4, Dordrecht, NE, pp.361-368			11/1/1993
CB		Lien, Jung-Cheun; Breuer, Melvin A., "A Universal Test and Maintenance Controller for Modules and Boards", IEEE Transactions on Industrial Electronics, Vol. 36, No. 2, May 1989, pp. 231-240			5/1/1989
CB		Lofstrom, Keith, "A Demonstration IC for the P1149.4 Mixed-Signal Test Standard", IEEE International Test Conference 1996, Paper 4.2, pp.92-98			1/1/1996
CB		Lofstrom, Keith, "Early Capture for Boundary Scan Timing Measurements", International Test Conference 1996, October 20-25, 1996, pp. 417-422			10/20/1996
CB		Maierhofer, J., "Hierarchical Self-Test Concept Based on the JTAG Standard", IEEE International Test Conference 1990, Paper 5.2, pp.127-134			1/1/1990
CB		Marinissen, Erik Jan, IEEE P1500 Core Test Standardization, Philips Research Laboratories, November, 1997, P1500 Meeting, ITC Test Week, Washington, D.C.			11/1/1997
CB		Marlett, et al., "RISP Methodology", Electronic Engineering, February, 1989, pp.45-48			2/1/1989
CB		Marwedel, Peter, "Processor-Core Based Design and Test", IEEE 0-7803-3662-3/97, 1997 IEEE			1/1/1997
CB		Maunder, C., "A Universal Framework for Managed Built-In Test", International Test Conference 1993, Jan. 1, 1993, pp. 21-29, 1993 IEEE.			1/1/1993
CB		Maunder, Colin, and Beenker, Frans, "Boundary-Scan: A Framework for Structured Design-for-Test," paper 30.1, International Test Conference 1987 Proceedings, Sep. 1-3			9/1/1987
CB		Mixed-Signal Working Group, "Standard for a Mixed Signal Test Bus", D11, March 1997, pp.1-51			3/1/1997
CB		Ohletz, et al., "Overhead in Scan and Self-testing Designs", International Test Conference, 1987, Sep. 1-3, pp. 460-470			9/1/1987
EXAMINER 				DATE CONSIDERED 8-11-05	
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Form PTO 1449 A MAY 27 2005 					
<b>OTHER DOCUMENTS</b> (Including Author, Title, Date, Pertinent Pages, Etc.)					
cb		Ohsawa, et al., "A 60-ns \$-Mbit CMOS DRAM with Built-In self-Test Function", IEEE Journal of Solid-State Circuits, Vol. SC-22, No. 5, October 1987, pp. 663-668	10/1/1987		
cb		Paraskeva, et al., "New Test Structure for VLSI Self-Test: The Structured Test Register", 8030 Electronic Letters, 21 (1985) sept. No. 19, Stenenage, Herts, Great Britain, July 26, 1985	7/26/1985		
cb		Parker, "The Impact of Boundary Scan on Board Test", IEEE design & Test of Computers, August, 1989, pp. 18-30	8/1/1989		
cb		Parker, Kenneth, et al., "Structure and Methodology for an Analog Testability Bus", IEEE International Test Conference 1993, Paper 15.2, pp. 309-322	1/1/1993		
cb		Pradhan, M.M., et al., "Circular BIST with Partial Scan," 1988 International Test Conference, Sept. 12-14, 1987, Paper 35.1, pp. 719-727	9/12/1987		
cb		Russell, "The JTAG Proposal and Its Impact On Automatic Test", ATE & Instrumentation Conference, Sept, 1988, pp. 289-297	9/1/1988		
cb		Sabo, et al., "Genesil Silicon Compilation and Design For Testability", IEEE Custom Integrated Circuits Conference, May 12-15, 1986, pp. 416-420	5/12/1986		
cb		Sasidhar, K, Chatterjee, A., Zorian, Y., "Optimal Multiple Chain Relay Testing Scheme for MCMs on Large Area Substrates," 1996 IEEE International Test Conference, Paper 31.1, pp. 818-827	1/1/1996		
cb		Sasidhar, K, Chatterjee, A., Zorian, Y., "Relay Propagation Scheme for Testing of MCMs on Large Area Substrates," 1996 IEEE 1066-1409/96, pp. 131-135	1/1/1996		
cb		Sellers, et al., "Error Detecting Logic for Digital Computers", McGraw-Hill Co., 1968 pp. 207-211	1/1/1968		
cb		Sharp, John, "JTAG Emulation Systems Explore Embedded Cores," pp. 62, Electronic Engineering Times, June 15, 1998	6/15/1998		
cb		Sunter, S.K., "Cost/Benefit Analysis of the P1149.4 Mixed-signal Test Bus", IEE Proceedings, Circuits, Devices, Systems, Vol. 143, No. 6, December, 1996, pp. 393-398	12/1/1996		
cb		Sunter, Stephen, "A Low Cost 100 MHz Analog Test Bus", IEEE 1995, pp.60-65	1/1/1995		
cb		Tanenbaum, Andrew S., Structured Computer Organization, Prentice-Hall, 1984, pp. 10-12	1/1/1984		
cb		Texas Instruments Data Book, 1991, "Advanced Logic Bus Interface Logic", pp.11-3, 11-11,11-18, 11-19, 11-23, 11-82, 11-83, 11-84, 11-85	1/1/1991		
cb		van Riessen, R. P., Kerkhoff, H. G., Kloppenburg, A., "Design and Implementation of a Hierarchical Testable Architecture Using the Boundary Scan Standard", Proceedings, 1 <sup>st</sup> European Test Conference, Paris, France, April 12-14, 1989, pp. 112-118	4/12/1989		
cb		Wagner, "Interconnect Testing With Boundary Scan", International Test Conference Proceedings, 1987, Sep. 1-3, pp. 52-57	9/1/1987		
cb		Wang, et al., "Concurrent Built-In Logic Block Observer (CBILBO)", IEEE International Symposium On Circuits and Systems", May 5-7, 1986, Vol. 3, pp. 1054-1057	5/5/1986		
EXAMINER <i>Cynthia Beith</i>				DATE CONSIDERED 8-11-05	
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<b>OTHER DOCUMENTS</b> <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>					
CB		Wang, Laung-Terng; Marhoefer, Michael; McCluskey, Edward, J., "A Self-Test and Self-Diagnosis Architecture for Boards Using Boundary Scan", Proceedings 1 <sup>st</sup> European Test Conference, Paris, April 12-14, 1989, pp. 119-126		4/12/1989	
CB		Whetsel, , Lee, "An IEEE 1149.1 Based Test Access Architecture for ICs With Embedded Cores", International Test Conference 1997, Nov. 1-6, 1997, pp. 69-78		11/1/1997	
CB		Whetsel, Lee, "An IEEE 1149.1 Based Test Access Architecture For ICs With Embedded Cores", International Test Conference 1997, November 1-6, 1997, pp. 69-78		11/1/1997	
CB		Whetsel, Lee, "Improved Boundary Scan Design", IEEE International Test Conference 1995 Proceedings, October 21-25, 1995, Paper 36.2, pp. 851-860		10/21/1995	
CB		Whetsel, Lee, "A Proposed Standard Test Bus and Boundary Scan Architecture", IEEE International Conference on Computer Design: VLSI in Computers & Processes, Oct. 3-5, 1988, pp. 330-333		10/3/1988	
CB		Whetsel, Lee, "A Standard Test Bus and Boundary Scan Architecture," pp. 48-59, Texas Instruments Technical Journal, July-August 1988, Vol. 5, No. 4		7/1/1988	
CB		Whetsel, Lee, "A View of the JTAG Port and Architecture", ATE & Instrumentation Conference West, Jan. 11-14, 1988, pp. 385-401		1/11/1988	
CB		Whetsel, Lee, "Addressable Test Ports: An Approach to Testing Embedded Cores," 1999 ITC & TI Test Symposium, Sept. 28-30, 1999		9/28/1999	
CB		Whetsel, Lee, "An IEEE 1149.1 Based Logic/Signature Analyzer in a Chip," International Test Conference 1991 Proceedings, October 26-30, 1991		10/26/1991	
CB		Whetsel, Lee, "IEE STD. 1149.1 - An Introduction", NEPCON, February, 1993, 10 pages		2/1/1993	
CB		Whetsel, Lee, "JTAG Compatible Devices Simplify Board Level Design For Testability," 8080 Wescon Conference Record 33 (1989) November, pp. 294-299		11/1/1989	
CB		Winters, Mike, "Using IEEE-1149.1 For In-Circuit Emulation", WESCON/1994, pp.525-528, 27-27 SEP 1994		9/27/1994	
CB		Zorian, Yervant; Jarwala, Najmi, "Designing Fault-Tolerant, Testable, VLSI Processors Using the IEEE P1149.1 Boundary Scan Architecture", 7 <sup>th</sup> IEEE International Conference on Computer Design: VLSI in Computers & Processes, October 2-4, 1989		10/2/1989	
EXAMINER <i>Cynthia Butth</i>			DATE CONSIDERED <i>8-11-05</i>		
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